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| Notice of References Cited | Application/Control No. 10/045,414 | Applicant(s)/Patent Under Reexamination MIKAEL ET AL. | |
| | Examiner Malcolm D. Cribbs | Art Unit 2115 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|----------------------|----------------|
| * | A | US-6,493,805 | 12-2002 | Nieuwland et al. | 711/152 |
| * | B | US-2003/0061259 | 03-2003 | Heddes et al. | 709/102 |
| * | C | US-7,036,125 | 04-2006 | Basso et al. | 718/104 |
| * | D | US-6,170,018 | 01-2001 | Voll et al. | 719/330 |
| * | E | US-4,590,555 | 05-1986 | Bourrez, Jean-Marie | 718/103 |
| * | F | US-6,237,019 | 05-2001 | Ault et al. | 718/104 |
| * | G | US-6,131,094 | 10-2000 | Gord, William Eugene | 707/8 |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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